

From:

Wayne Schmidt *W Schmidt*

To:

Ext

"Doddcv@~~_____~~"

J Baker

Date:

Tue, Jul 11, 2000 12:43 PM

Ex. 6

Subject:

Re: Question?

Thanks Caius - I just got done reading your file INDIAN~6.NRR and you say the following about R2C5 .

The defect signal sits on a noise ridge that runs the length of the tube. This noise ridge is about 1-volt in amplitude and measures as a deep id defect, on the order of 70 to 100% deep. This ridge makes both the detection and sizing of this defect more difficult. In Figure 5 we show the lissajous of the noise ridge. The signal-to-noise is slightly better for the 400 kHz frequency than the 300 kHz.

I assume that the Lissajous for the noise signal make it clear that it is noise and not a defect and that the Lissajous for the defect area makes it clear that there is a defect and not noise.

My questions is, if you have a noise signal that can be taken as a ID flaw at 70- 100% deep - how in the world do you know without checking the Lissajous for the entire area of noise that there is not a defect. If you did not check it would you not have to assume that the defect was at the noise level.

What If the noise signal measured as an ID defect at > 60% TW and there was a defect that did not push above the noise signal (50% TW), the noise actually masked it entirely. First, could the lissajous have found the defect. If so would it be expected to run the examination point through the entire area of concern? If not, would you have to assume that there was a defect that was at least at the level equivalent to the noise (ie., >60% TW)

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CC:

Cheryl Beardslee, Edmund Sullivan, Stephanie Coffin